

**Participants of the 3rd EMVA Business Conference
from 29th - 30th May, 2005
in Palermo, Italy
Status of May 12, 2005**



Name	Company/Organisation	Country
Adams, Larry	Advanced Imaging	USA
Aimonen, Pertti	Atostek Ltd.	Finland
Avenel, Jerome	Sony France S.A.	France
Bake, Arndt	Basler AG	Germany
Bartfai, Dr. Gusztav	Analogic Computers Ltd.	Hungary
Beernink, Franc	SPC Company	Netherlands
Beising, Michael	SAC GmbH	Germany
Braggins, Don	UK Industrial Vision Association	United Kingdom
Brown, Bud	Intercon 1 Nortech Systems	USA
Bush, Kathy	Vision Systems Design	USA
Bylek, Johann	PennWell Corporation	Germany
Cameron, Drew	Europa Science	United Kingdom
Campbell, Thomas	Sensor Technologies America Inc.	USA
Carstensen, Dr. Michael	Videometer A/S	Denmark
Clark, Warren	Europa Science	United Kingdom
Colet, Philip	Coreco Imaging Inc.	Canada
Cucchetti, Ettore	COGNEX Germany, Inc.	Germany
de la Maza, Jesus	innovalia	Spain
Deans, Gordon	Adept Technology, Inc.	Canada
Destruels, Arnaud	Sony SES	France
Diani, Marco	Image S S.R.L.	Italy
Drews, Kirsten	Siemens AG	Germany
Ersü, Enis	ISRA VISION SYSTEMS AG	Germany
Fenwick-Smith, Robert	Tattile S.r.L.	Italy
Friedrich, Michael K.	Volpi AG	Switzerland
Galliani, Carlo	Univision	Italy
Gökstorp, Mats	SICK IVP AB	Sweden
Grotepaß, Dr. Jürgen	Freudenberg Dichtungs- und Schwingungstechnik KG	Germany
Gruber, Bernhard	QUISS GmbH	Germany
Hartmann, Jürgen	IDS Imaging Development Systems GmbH	Germany
Heinol, Dr. Horst G.	Asentics GmbH & Co. KG	Germany
Heinrichs, Jean-Pierre	NET GmbH	Germany
Hermans, Dr. Lou	Cypress Semiconductor	Belgium
Ilsby, Henrik	JAI A/S	Denmark
Jansen, Gabriele	ISRA VISION SYSTEMS AG	Germany
Jochum, Dr. Johannes	GIT VERLAG GmbH	Germany
Justen, Jarmo	Orbis OY	Finland
Kani, Naoyuki	Japan F.A. Systems Corporation	Japan
Kent, Ched	Parameter AB	Sweden
Klinger, Dr. Matthias	Vision & Control GmbH	Germany
Konaka, Hideaki	Toshiba teli, Inc.	Japan
Krüger, Prof. Dr.-Ing. Jörg	Fraunhofer IPK Berlin	Germany
Landolt, Jeannette	Photonfocus AG	Switzerland
Lee, Malcolm	Navitar	USA
Lewerendt, Ingo	Allied Vision Technologies GmbH	Germany
Ley, Dr.-Ing. Dietmar	Basler AG	Germany
Longoni, Milena	Image S S.R.L.	Italy
Lüttmann, Dorothee	EMVA	Germany

Name	Company/Organisation	Country
Mangold, Rene	Photonfocus AG	Switzerland
Massen, Prof. Dr.-Ing. Robert	MASSEN machine vision systems GmbH	Germany
McMillion, Sharon	Sensor Technologies America Inc.	USA
Melis, Joachim	Adept Technology GmbH	Germany
Modrich, Dr.-Ing. Kai-Udo	Fraunhofer Institut für Produktionstechnik und Automatisierung	Germany
Moss, Dr. Tuckermann	Laurin Publishing	United Kingdom
Nakamura, Kayo	Japan F.A. Systems Corporation	Japan
Nguyen, Valérie	E2V Technologies	France
Nickolay, Dr. -Ing. Bertram	Fraunhofer-Institut für Produktionsanlagen	Germany
Noffz, Dr. Klaus-Henning	Silicon Software GmbH	Germany
Ott, Dr. Emil	PCO AG	Germany
Pape, Katrin	National Instruments Germany GmbH	Germany
Pape,Volker	Viscom AG	Germany
Pelzer, Torsten	Viscom AG	Germany
Piacentini, Ignazio	Imaging Lab	Italy
Pisch, Michael	ICS Sony Deutschland GmbH	Germany
Plasswilm, Georg	National Instruments Germany GmbH	Germany
Pluta, René	Philips	Netherlands
Rauscher, Ernst	Rauscher GmbH	Germany
Roberts, Arwyn	Surface Inspection Ltd.	United Kingdom
Salgari, Roberto	PARVIS Systems and Services	Italy
Sartori, Alvise	NeuriCAM S.p.A.	Italy
Schaarschmidt, Andreas	STEMMER IMAGING GmbH	Germany
Schwarzkopf, Patrick	EMVA	Germany
Seyb, Dr. Holger	Basler AG	Germany
Sgro, Dr. Joseph	Alacron, Inc.	USA
Simon, Santiago	AIDO / Technological Institute of Optics	Spain
Soliman, Sayed	MaxxVision GmbH	Germany
Staerk, Henning	Allied Vision Technologies GmbH	Germany
Steenberg, Hans	Image House A/S	Denmark
Stella, Ettore	ISSIA CNR	Italy
Stemmer, Wilhelm	STEMMER IMAGING GmbH	Germany
Takaoka, Hiroshi	Toshiba teli, Inc.	Japan
Tassakos, Dr.Lambis	inos Automationssoftware GmbH	Germany
Theuwissen, Prof. Dr.Albert	DALSA Corp.	Netherlands
Thor, Wouter van	Adimec Advanced Image Systems, B.V.	Netherlands
Timmermans, Toine	Green Vision	Netherlands
Torabi, Dr. Bahram	SICK AG	Germany
Trapet, Dr. Eugen	UNIMETRIK	Spain
Trdic, Francelj	FDS Research	Slovenia
Van de Veere, Koenraad	Data@Vision Belux	Belgium
Ventura-Traveset, Antonio	DATAPIXEL S.L.	Spain
Wagner, Christoph	OBE	Germany
Walter, Thomas	Stuttgarter Messe- und Kongress GmbH	Germany
Wány, Martin	AWAIBA	Portugal
Wilkie, Dr. Tom	Europa Science	United Kingdom
Will, August	Micron Semiconductor Products, Inc.	USA
Yamanaka, Toshio	Toshiba teli, Inc.	Japan
Zeist, Gert van	Vision Light Tech	Netherlands
Zoeller, Thorsten	COGNEX Germany, Inc.	Germany
Zoll, Stephan	Asentics GmbH & Co. KG	Germany